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Peak power tracking in parallel connected convertors

Siri, K. Caliskan, V.A. Lee, C.Q.
Electron. Res. Lab., Illinois Univ., Chicago, IL ;

This paper appears in: Circuits, Devices and Systems, IEE Proceedings G
Publication Date: Apr 1993
Volume: 140, Issue: 2
On page(s): 106-116
ISSN: 0956-3768
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CODEN: IPGSEB
INSPEC Accession Number: 4397694
Posted online: 2002-08-06 18:41:32.0

Abstract
A control scheme for parallel connected convertor systems, which will transfer the maximum a from a nonideal voltage source, is presented. Monitoring the rates of change in both the avera and average input power from the source, the proposed control method can dynamically regul convertor system to track the peak power point of the source. The amplitude and frequency of due to a limit cycle around the system peak power point is analysed. To improve the system ef reliability, the central limit distribution control is incorporated into the proposed scheme to unifo supplied power among the parallel connected convertors

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IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

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